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(a) Celestry Design Technologies, Inc.	
	Name: Cadence Design Systems, Inc.
Additional name(s) of conveying party(ies) attached?	Street Address: 2655 Seely Avenue
Yes No	City: San Jose State: CA Zip: 95134
	Country: U.S.A.
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Security Agreement Change of Name	City: State: Zip:
Other	Country:
Execution Date: (a) 02/27/04	Additional name(s) & address(es) attached? ———————————————————————————————————
Application number(s) or patent number(s):	
If this document is being filed together with a new application, the	e execution date of the application is:
A. Patent Application No.(s) -	B. Patent No.(s)
Title: See Attached Exhibit A	.,
Additional num	bers attached? Yes No
Name and address of party to whom correspondence concerning document should be malled:	Total number of applications and patents involved: 10
Name: Gerald P. Parsons	
Internal Address: Parsons Hsue & de Runtz LLP	
Street Address: 655 Montgomery Street, Suite 1800	
City San Francisco State CA Zip 94111	7. Total fee (37 CFR 3.41): \$40.00
Old State CA Zip 94111	A check is enclosed that includes the total fee.
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8. Statement and signature.	
To the best of my knowledge and belief, the foregoing information original document.	on is true and correct and any attached copy is a true copy of the
Could B. Bosses Bos No. 04 400	P. P.
Gerald P. Parsons, Reg. No.: 24,486 Name of Person Signing	Signature March 22, 2004 Date

Total number of pages including cover sheet, attachments, and documents: 3

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<u>11(S)</u>	Lifeng Wu et al. Zhihong Liu, Jeong Y. Choi, Lifeng Wu, Alvin I. Chen, Gang Zhang	Jeong Y., Choi, Lifeng Wu, Alvin I. Chen	Lifeng Wu, Zhihong Liu, Alvin I. Chen,	Jeong Y., Choi, Bruce W. McGaughy	Jeong Y., Choi, Bruce W. McGaughy Zhihong Liu, Lifeng Wu, Jeong Y. Choi, Ping Chen, Alvin I. Chen, Gang Zhang	Jeong Y., Choi, Bruce W. M Zhihong Liu, Lifeng Wu, Je Ping Chen, Alvin I. Chen, C Lifeng Wu, Jeong Y. Choi, Jingkun Fang	Jeong Y., Choi, Bruce W., Zhihong Liu, Lifeng Wu,, Ping Chen, Alvin I. Chen, Lifeng Wu, Jeong Y. Choi Jingkun Fang Won-Young Jung	Jeong Y., Choi, Bruce W. M. Zbihong Liu, Lifeng Wu, Je Ping Chen, Alvin I. Chen, G Lifeng Wu, Jeong Y. Choi, Jingkun Fang Won-Young Jung Jianlin Wei, Lifeng Wu, I-H	Jeong Y., Choi, Bruce W. M. Zhihong Liu, Lifeng Wu, Je Ping Chen, Alvin I. Chen, G. Lifeng Wu, Jeong Y. Choi, Jingkun Fang Won-Young Jung Jianlin Wei, Lifeng Wu, I-H Lifeng Wu, Jianlin Wei, I-H
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Serial No.	60/236,865 60/236,587	60/236,586	- 09/832,933		69,185	69,185 69,186	69,185 69,186 87,027	- 09/969,185 - 09/969,186 - 60/387,027 - 60/387,294	- 09/969,185 - 09/969,186 - 60/387,027 - 60/387,294

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ASSIGNMENT

Celestry Design Technologies, Inc., a California corporation (hereinafter "Celestry"), is the record owner of the right, title and interest in and to the United States patent applications listed on Exhibit A hereto (hereinafter "the Patent Applications").

Cadence Design Systems, Inc, a Delaware corporation, (hereinafter "Cadence") desires to acquire such right, title and interest in the Patent Applications.

Therefore, effective January 15, 2003, for good and valuable consideration, the receipt of which is acknowledged, Celestry hereby assigns and transfers to Cadence its full right, title and interest in the Patent Applications, any patents resulting therefrom and to the technology described therein, including divisions, continuations, reissues, re-examined versions, extensions thereof, all rights of priority thereto, and the right to collect damages from any third parties incurred both before and after the effective date.

Executed this <u>27</u> day of February, 2004.

Secretary

State of California) ss

County of Santa Cla), a

On <u>February 27 2004</u> before me, <u>Judith Casamajor</u> personally appeared <u>R.L. Smith Mc Keithen</u> personally known to me or proved to me on the basis of satisfactory evidence to be the person(s) whose name(s) is(are) subscribed to the within instrument and acknowledged to me that he/she/they executed the same in his/her/their authorized capacity(ies), and that by his/her/their signature(s) on the instrument the person(s), or the entity upon behalf of which the person(s) acted, executed the instrument.

WITNESS my hand and official seal.

iania Clara County

PATENT REEL: 014450 FRAME: 0139 Parsons Hsue & DERUNTZ LLP

655 Montgomery Street, Suite 1800 San Francisco, Ca 94111 tel 415.318.1160 fax 415.693.0194

Date

March 22, 2004

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